

Title (en)  
INTEGRATED CIRCUIT TEST SOCKET

Title (de)  
TESTSOCKEL FÜR INTEGRIERTE SCHALTUNGEN

Title (fr)  
SUPPORT D'ESSAI DE CIRCUITS INTÉGRÉS

Publication  
**EP 1907868 B1 20100825 (EN)**

Application  
**EP 06786727 A 20060707**

Priority  
• US 2006026668 W 20060707  
• US 18094305 A 20050712

Abstract (en)  
[origin: US7108535B1] A test socket is provided for use in testing integrated circuits, especially integrated circuits in BGA packages. The test socket comprises a base member and a cover member configured to move vertically between an upper position and a lower position with respect to the base member. Springs are positioned between the base member and the cover member and configured to bias the cover member in the upper position. A lever is coupled to the base member and to the cover member and is configured to pivot to an open position when the cover member is in the lower position and to pivot to a closed position to confine an integrated circuit within the base member when the cover member is in the upper position.

IPC 8 full level  
**G01R 31/319** (2006.01); **G01R 1/04** (2006.01)

CPC (source: EP KR US)  
**G01R 1/04** (2013.01 - KR); **G01R 1/0433** (2013.01 - EP US); **G01R 1/0466** (2013.01 - EP US); **H01R 12/88** (2013.01 - EP US);  
**H01R 2201/20** (2013.01 - EP US)

Designated contracting state (EPC)  
DE FR GB

DOCDB simple family (publication)  
**US 7108535 B1 20060919**; CN 101233415 A 20080730; CN 101233415 B 20110928; DE 602006016445 D1 20101007;  
EP 1907868 A2 20080409; EP 1907868 B1 20100825; JP 2009501340 A 20090115; JP 4757917 B2 20110824; KR 100962702 B1 20100611;  
KR 20080024227 A 20080317; TW 200712497 A 20070401; WO 2007008754 A2 20070118; WO 2007008754 A3 20070405

DOCDB simple family (application)  
**US 18094305 A 20050712**; CN 200680027635 A 20060707; DE 602006016445 T 20060707; EP 06786727 A 20060707;  
JP 2008521484 A 20060707; KR 20087002579 A 20060707; TW 95125436 A 20060712; US 2006026668 W 20060707